• '					Application/Control No.		Applicant(s)/Pat nt Und r R examination FUJIWARA, KENSUKE		
•		Notice of Refer	ences Cited	1	09/280,518 Examin r			490VE	
							Art Unit	Page 1 of 1	
		· · ·		LI C DA	David Yockey TENT DOCUMENTS		2861		
*				U.S. PA			T	DOCUM	ENT
		DOCUMENT NO.	DATE		NAME	CLASS	SUBCLASS	SOURCE ** APS OTHER	
	Α	6,104,986	Aug. 2000	Arevalo		702	120	⊠ ⊠	
	В								
_									
	D								
	Ε								
	F								
	G								
	Н								
	ı				•				
	J								
	К								
	L								
	М								
		FOREIGN PATENT DOCUMENTS						DOCUME	-NT
*		DOCUMENT NO.	DATE	COUNTRY	NAME	CLASS	SUBCLASS	SOURCE **	
				_	_			APS	OTHER
	N	4-255874	Sep. 1992	Japan	Robert	G03G	15/04		
	0		1						
	Р								
	Q								
	R	***							
	s	, , , , , , , , , , , , , , , , , , , ,							
	Т								
	Ι			NON-PA	TENT DOCUMENTS			DOCUME	ENT
*		DOCUMENT (Including Author, Title Date, Source, and Pertinent Pages)						SOURCE	**
						······································		APS	OTHER
	U								
	٧								
	8	v							
	х								

^{*}A copy of this reference is not being furnished with this Office action. (See Manual of Patent Examining Procedure, Section 707.05(a).)

*APS encompasses any electronic search i.e. text, image, and Commercial Databases.

U.S. Patent and Trademark Office

PTO-892 (Rev. 03-98)

Notice of References Cited